

<b>Notic of References Cited</b>	Application/Control No. 10/605,327	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Tuan T. Lam	Art Unit 2816	Page 1 of 1

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	C	US-6,549,075	04-2003	Zhang, Weibiao	330/282
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.